

Silicon Photonics : Industrial Reality and Future Evolutions

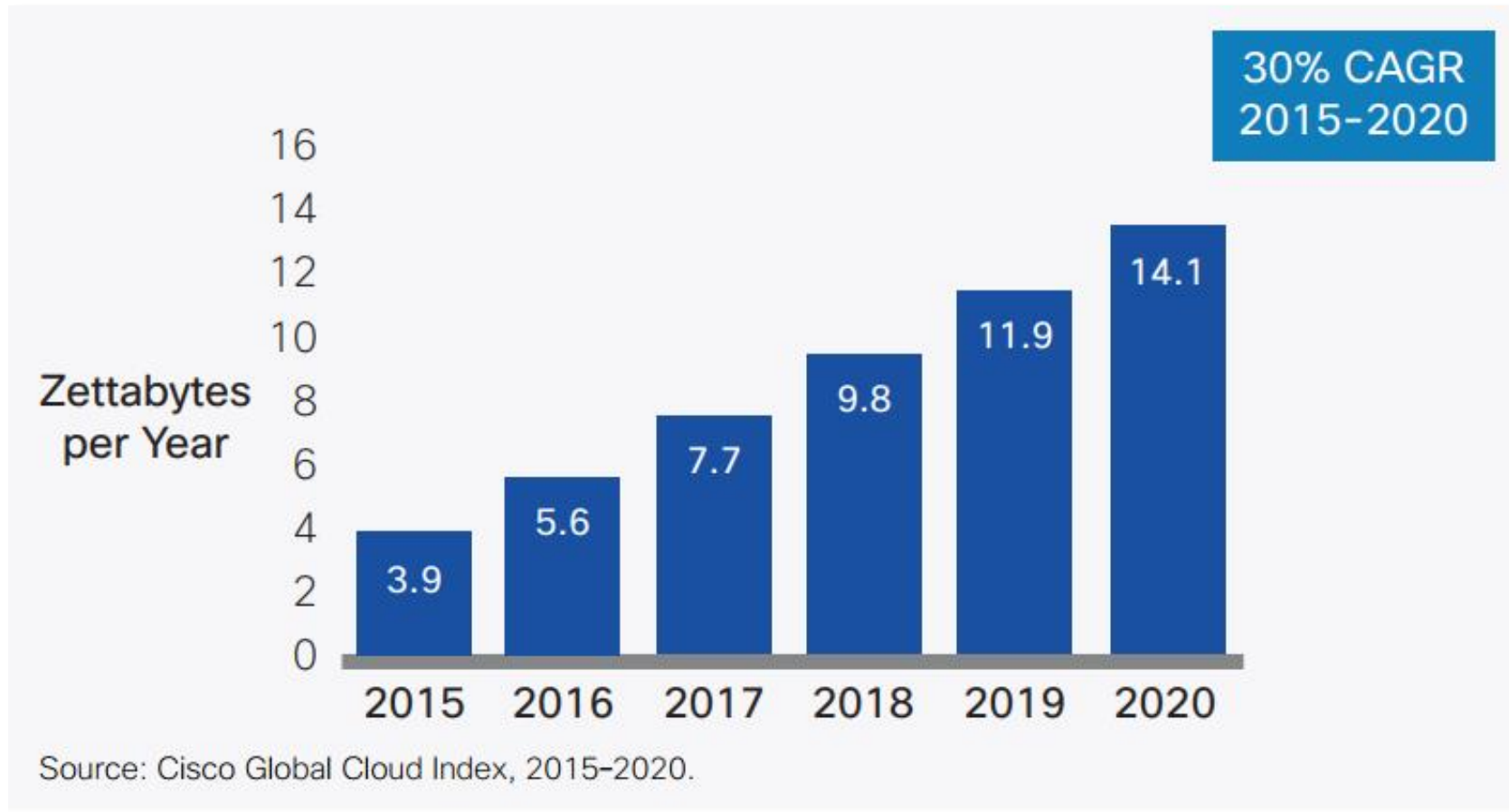
Frédéric BOEUF

STMicroelectronics, Crolles



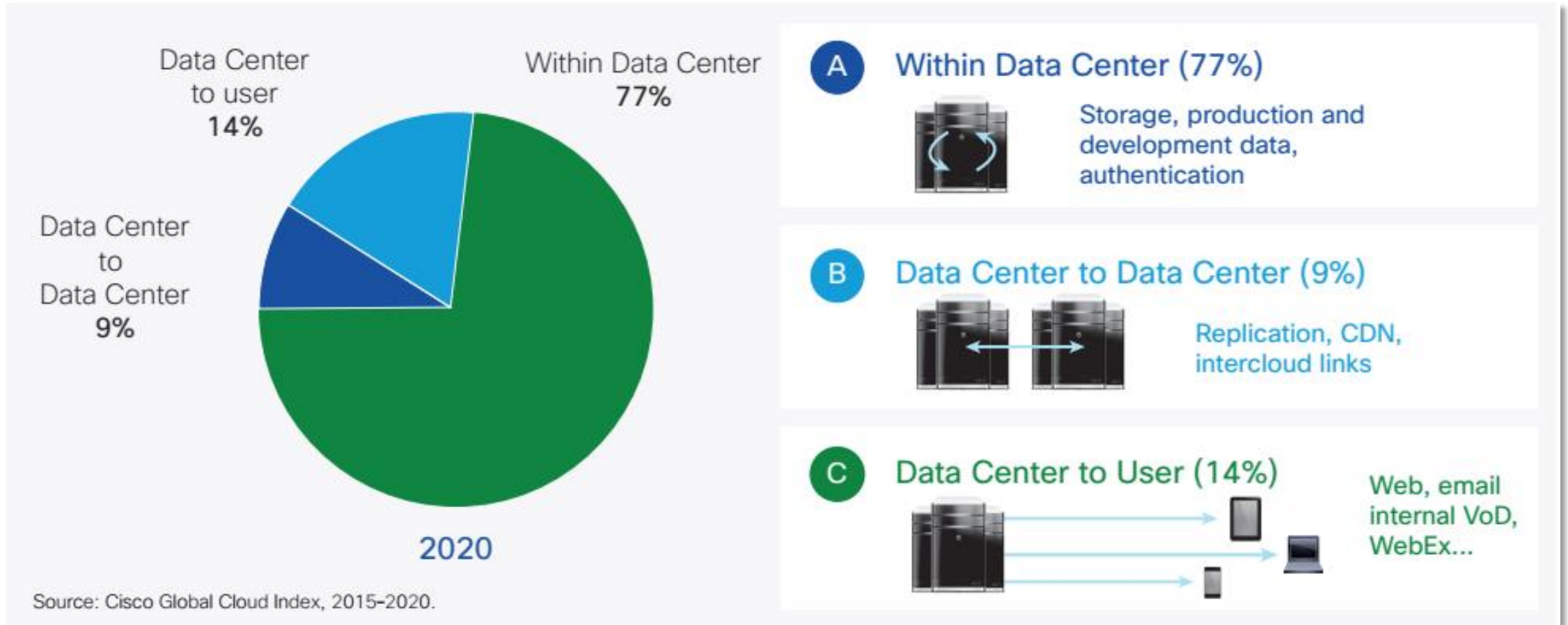
- I - Introduction
- II - Silicon-Photonics in Datacenters
- III - Technology Platform for 200G & 400G
- IV - Future Evolutions
- V - Conclusion

Traffic in Data Centers : the ZettaByte era



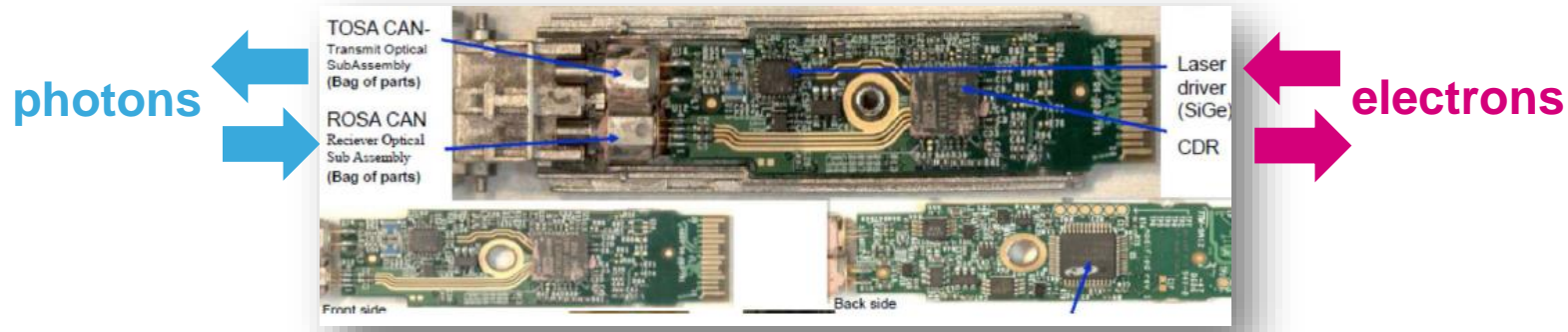
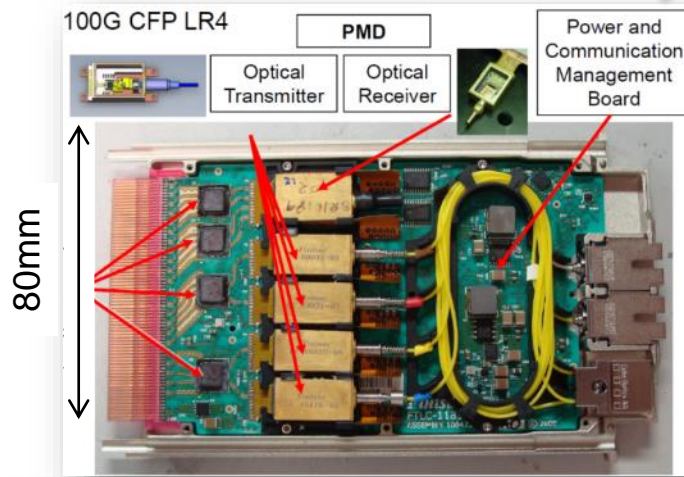
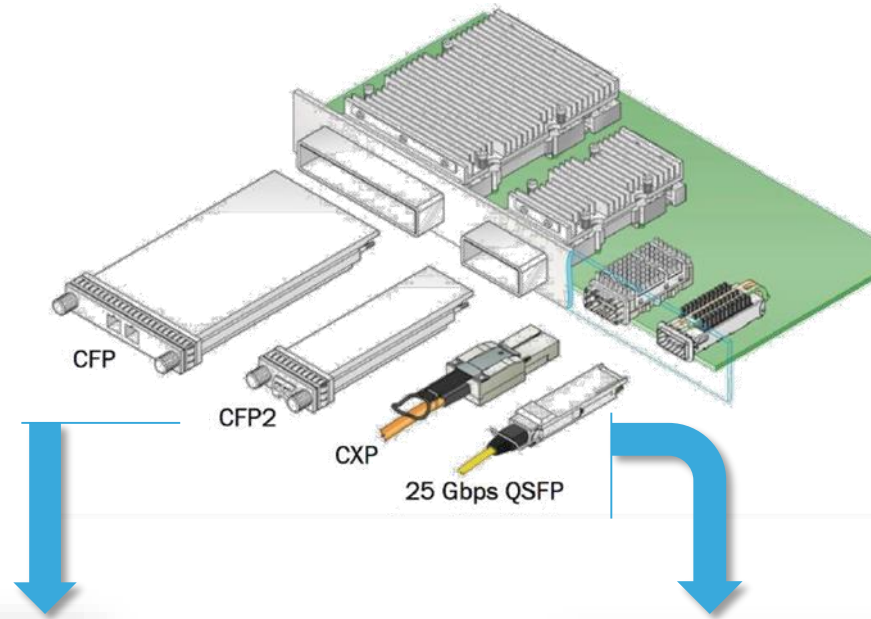
Traffic in datacenters is doubling every 3 years

Traffic growth is indise the Datacenters



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Example of Pluggable Optics



- TX : Modulated laser source or laser+external modulator
- RX : Photodiodes
- Driving electronics and TIA

Increasing Optical Communication Use

III-V → Si



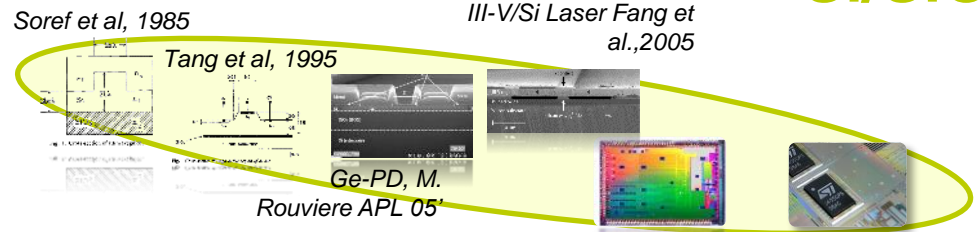
90% CMOS/BiCMOS (Si)

Started in middle of 80s : Si-Photonics

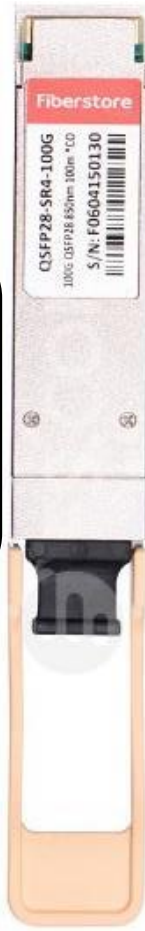
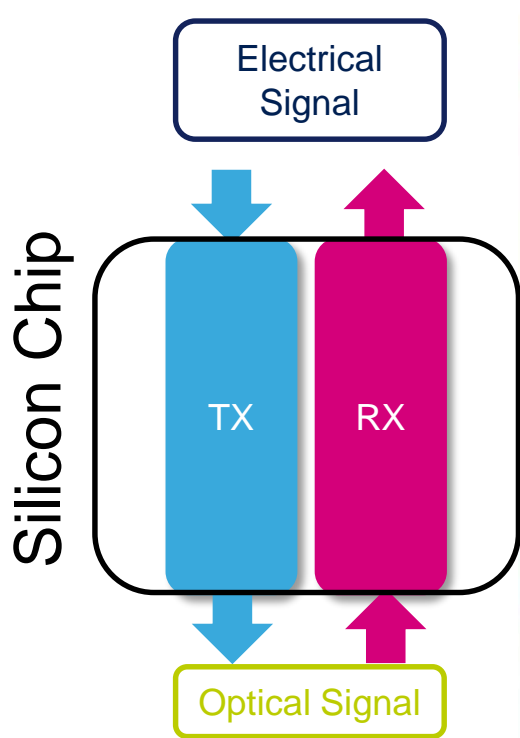
- Transparency of Si in telecom wavelength range
- Silicon On Insulator (SOI) wafer
- High-index contrast ($n_{Si}=3.5 - n_{SiO_2}=1.5$)
 - Strong light confinement

- Indirect bandgap material
 - Lacks efficient light emission

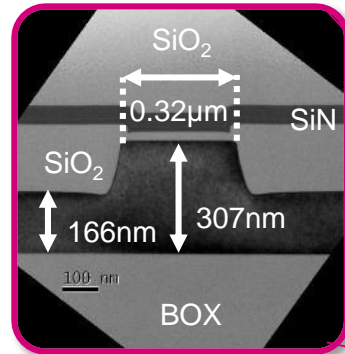
Si/SiO2



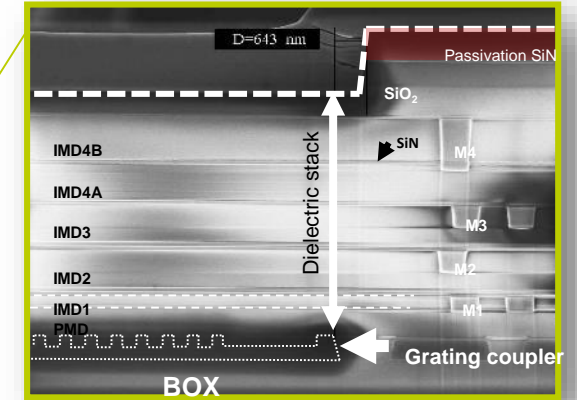
ST's 100G PSM4 - PIC25G Technology



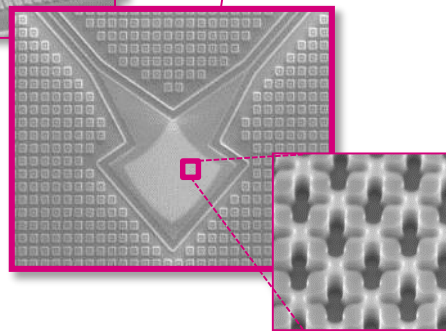
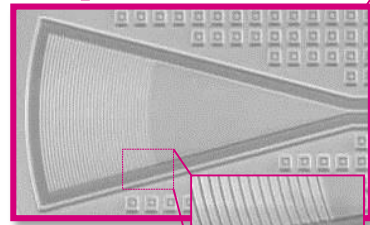
Passives



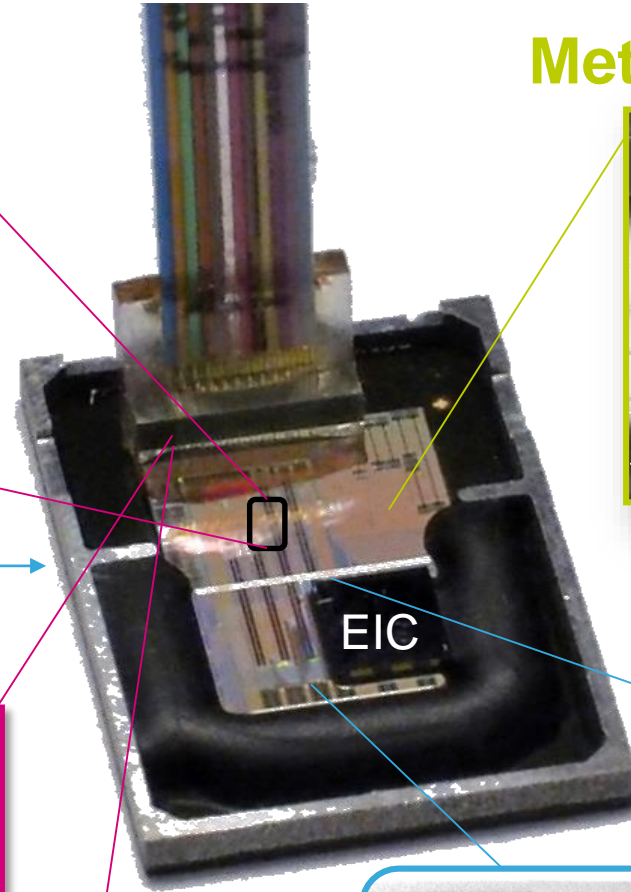
Metallic Interconnects



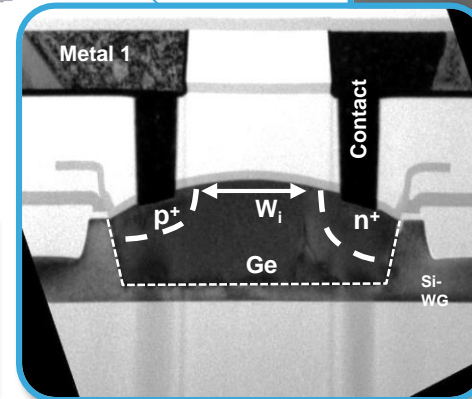
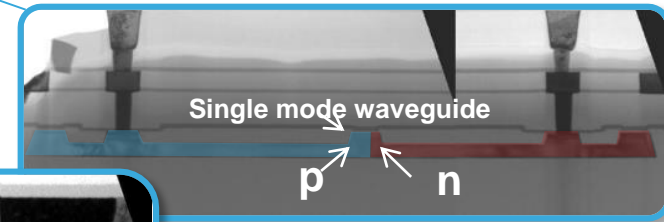
Optical I/O



EIC

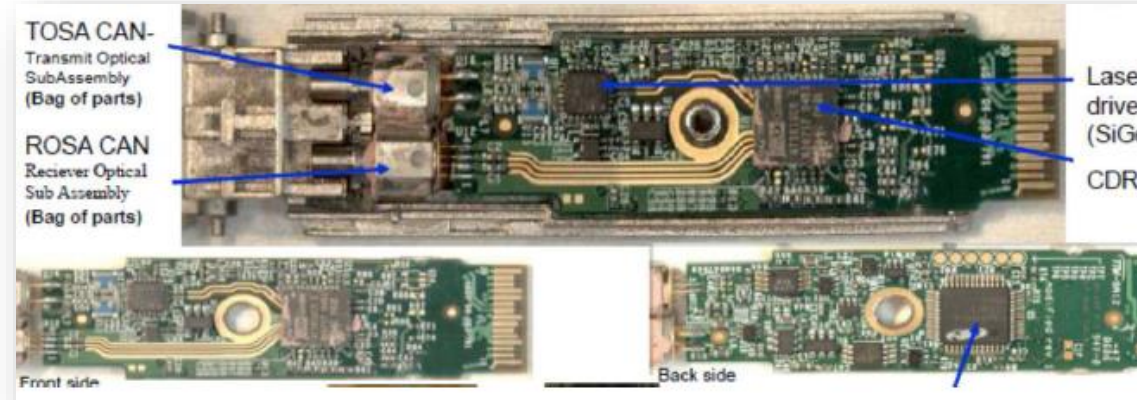


Active Devices

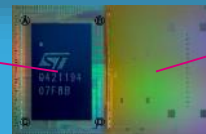


ST 100G PSM-4 Si-Photonics in QSPF28

Optical Module based on discrete components



B55



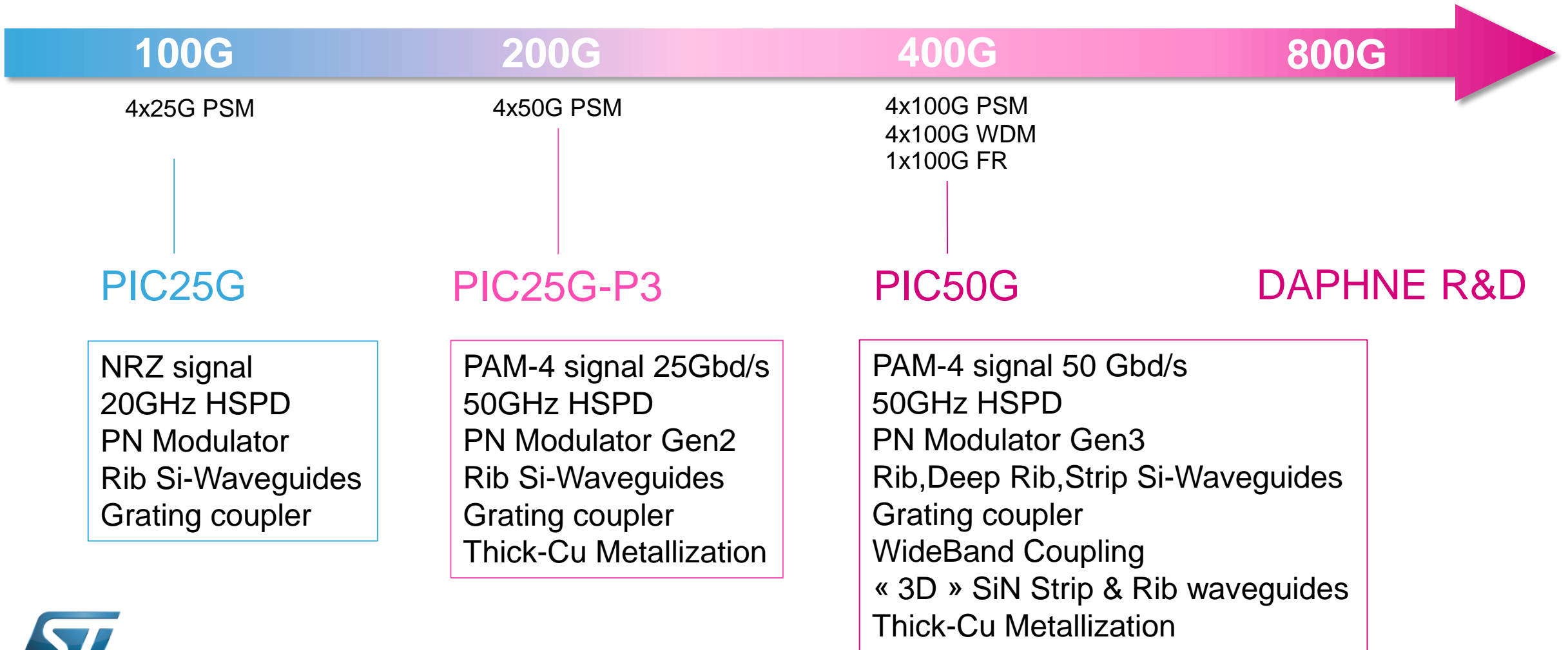
PIC25G



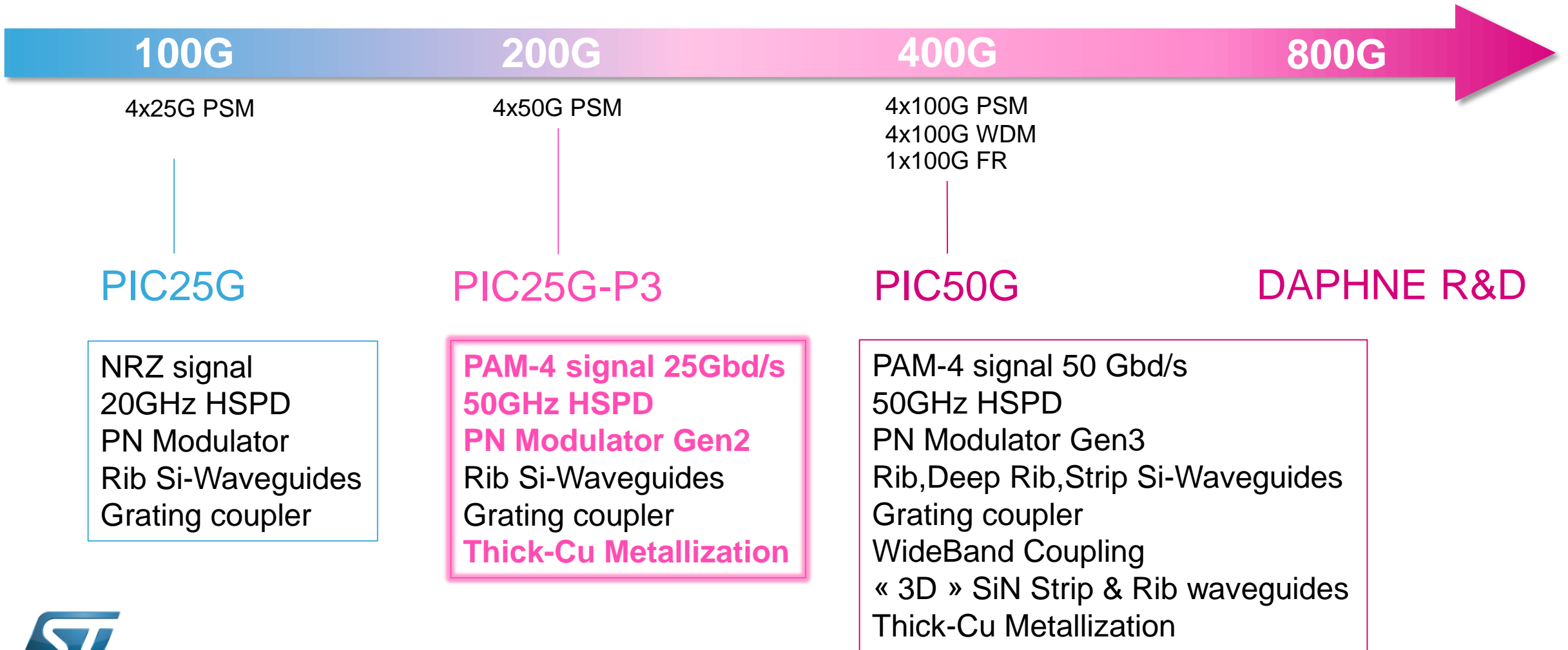
Si-Photonics Optical Module

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Si-Photonics Market vs ST-Technologies

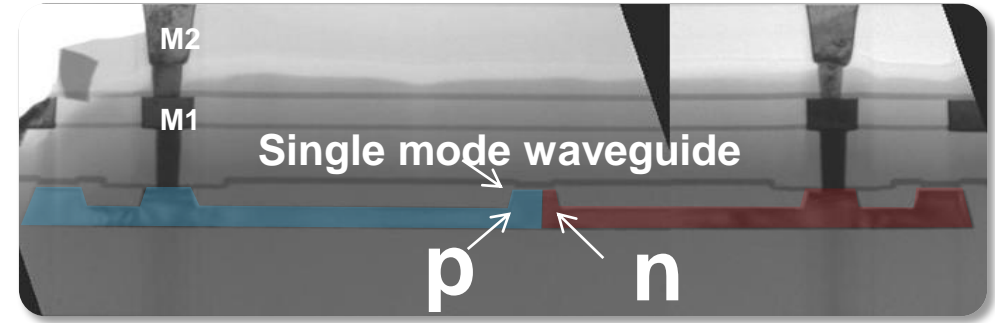
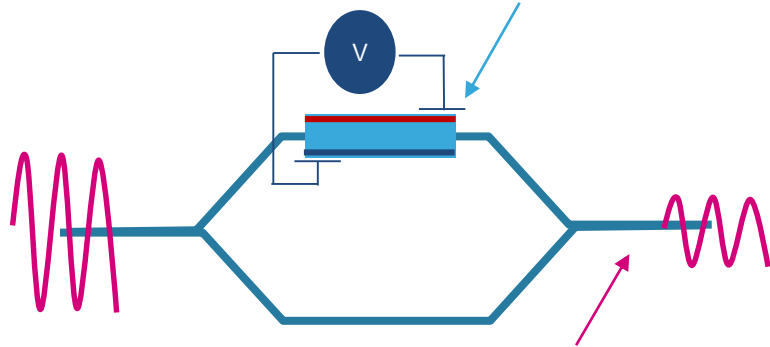


Si-Photonics Market vs ST-Technologies



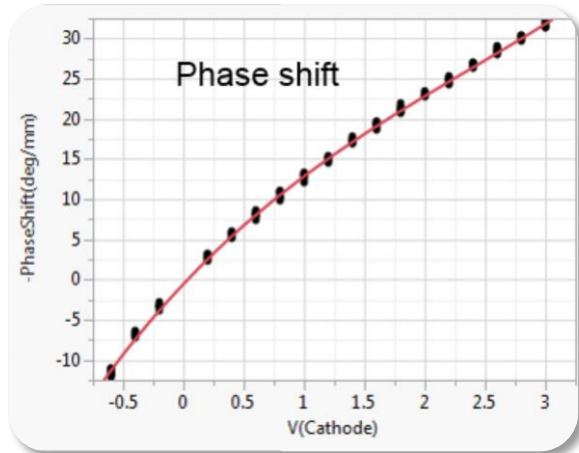
Gen2 Carrier Depletion Based High-Speed Phase Shifter

Phase shift = refractive index change



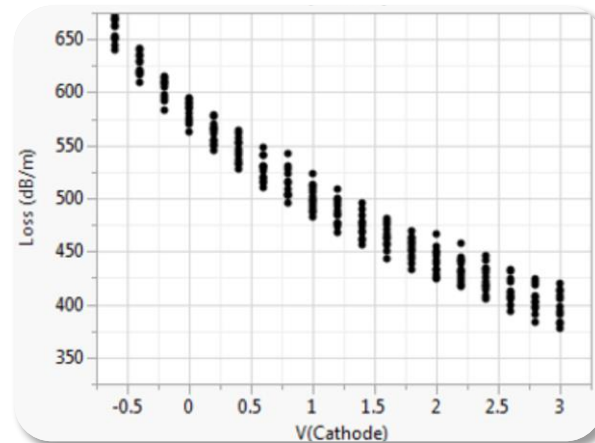
Amplitude modulation using interferometer

$\Delta\phi$: Phase Shift



~20°/mm@1.8V
(+ 50 % vs GEN1)

α : Loss



0V~0.57dB/cm@0V

Higher is better

$$\beta = \frac{\Delta\phi / \text{mm}}{\alpha / \text{mm}}$$

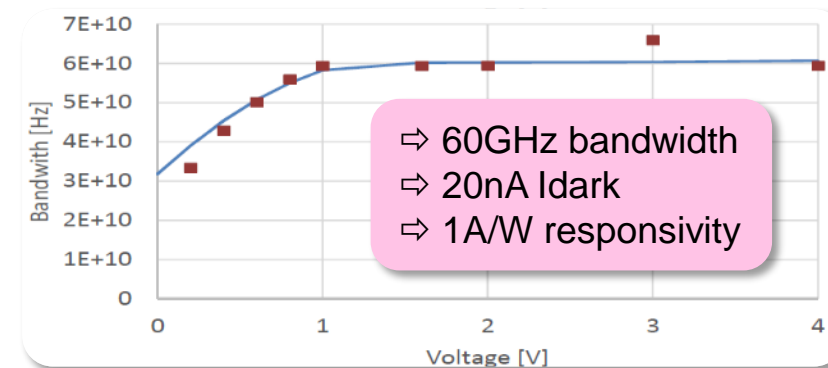
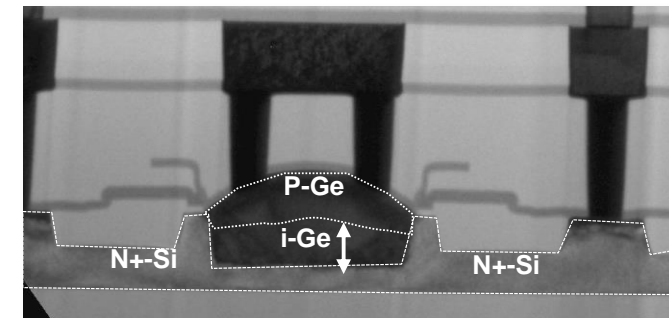
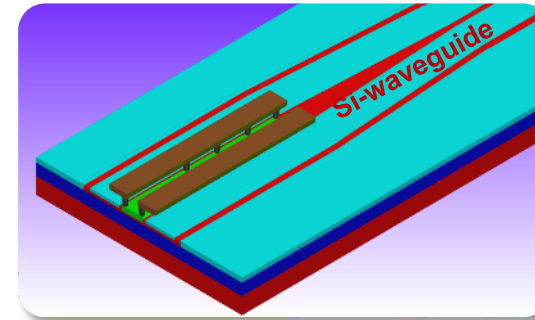
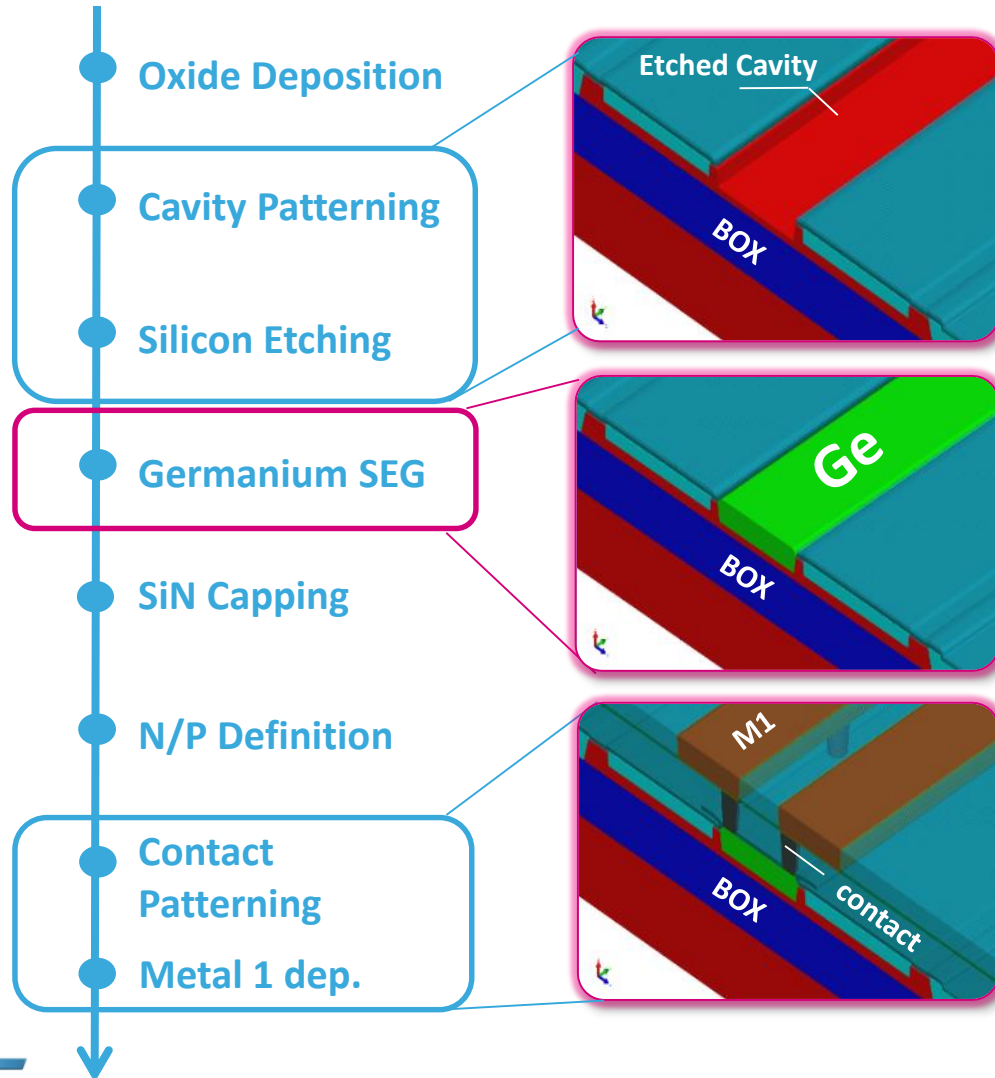
Lower is better



Improved TX efficiency

High Speed 60GHz Photodiode

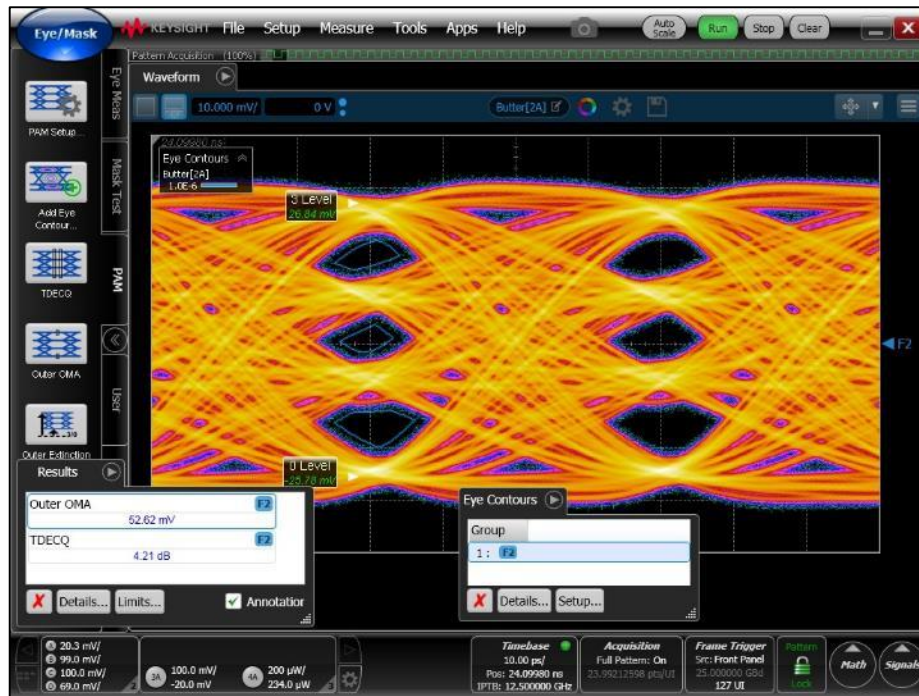
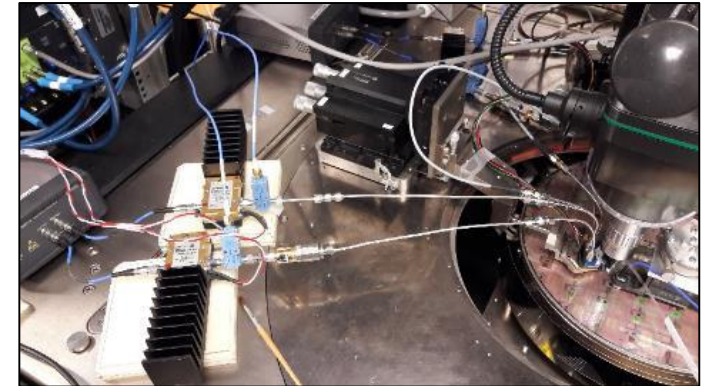
Photodiode



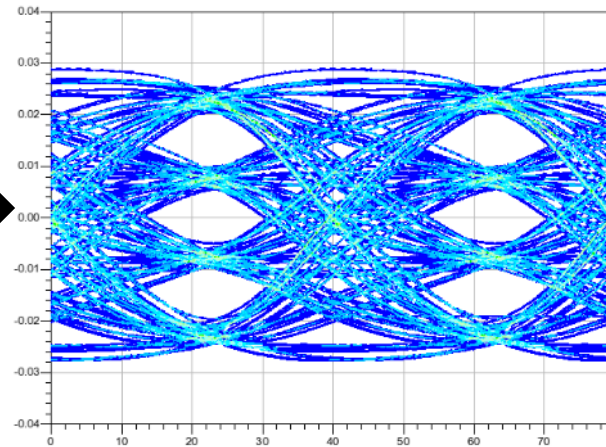
On Wafer TX 25Gbaud-PAM-4 (50Gbits/s)

PAM modulation = 4 states = 2 bits/symbol

Eye + BER contour @ HSPD: 25GBaud PAM4

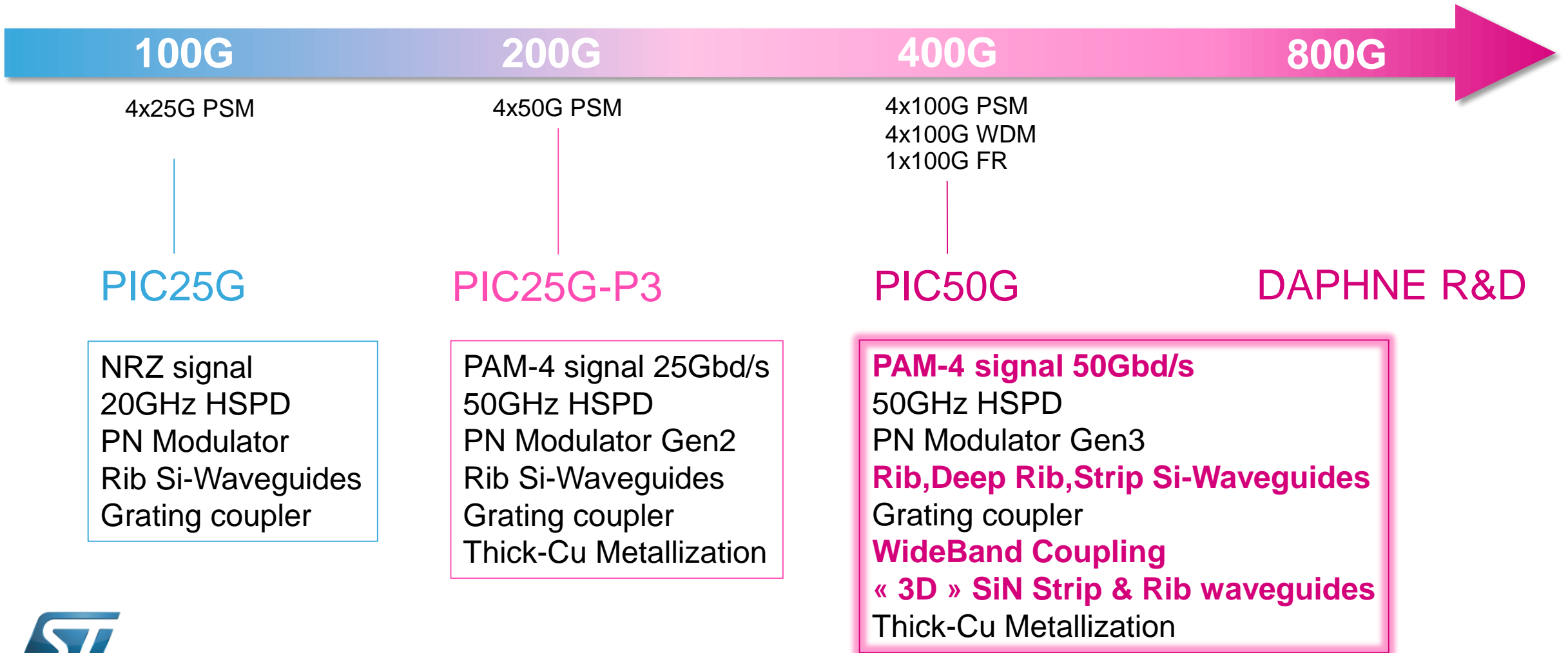


Retro-Simulations



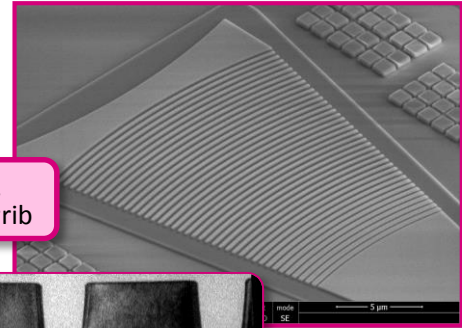
J.F Carpentier & P. Lemaitre

Si-Photonics Market vs ST-Technologies

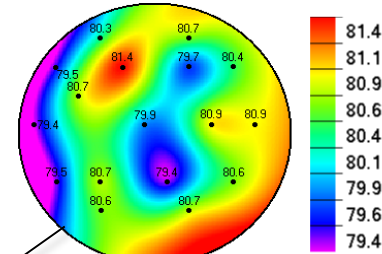
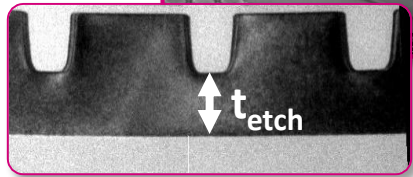


Challenge : Silicon Patterning Uniformity

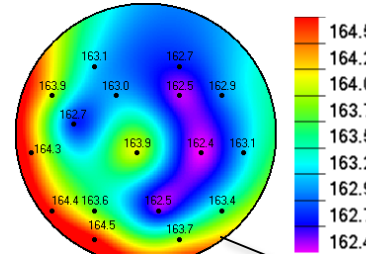
Trench Width Uniformity



$$\Delta\lambda \approx \Delta t_{\text{rib}}$$

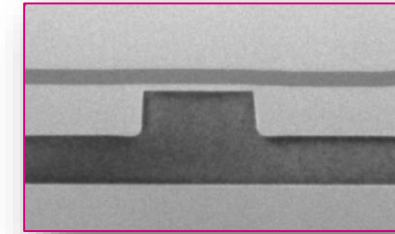


Mean : 80.3 nm
3-sigma : 1.8 nm (2.3 %)
Range : 2.0 nm (2.5 %)

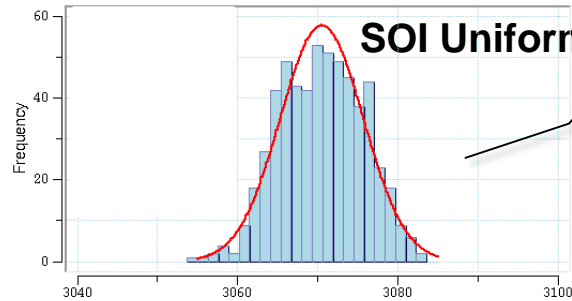


Mean : 163.3 nm
3-sigma : 2.1 nm (1.3 %)
Range : 2.1 nm (1.3 %)

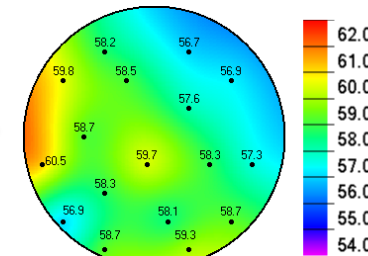
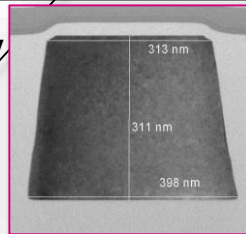
Partial Etch Depth Uniformity



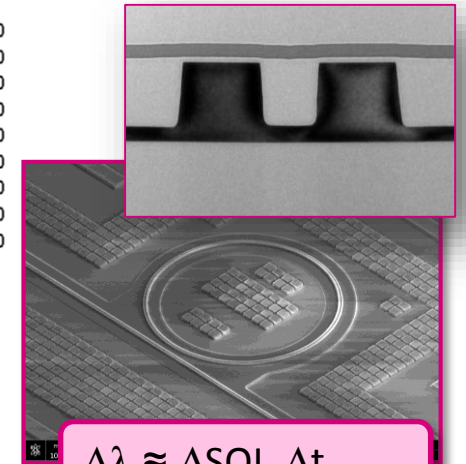
Deep Etch Depth Uniformity



SOI Uniformity



Mean : 58.4 nm
3-sigma : 3.2 nm (5.5 %)
Range : 3.8 nm (6.4 %)



$$\Delta\lambda \approx \Delta\text{SOI}, \Delta t_{\text{drib}}$$

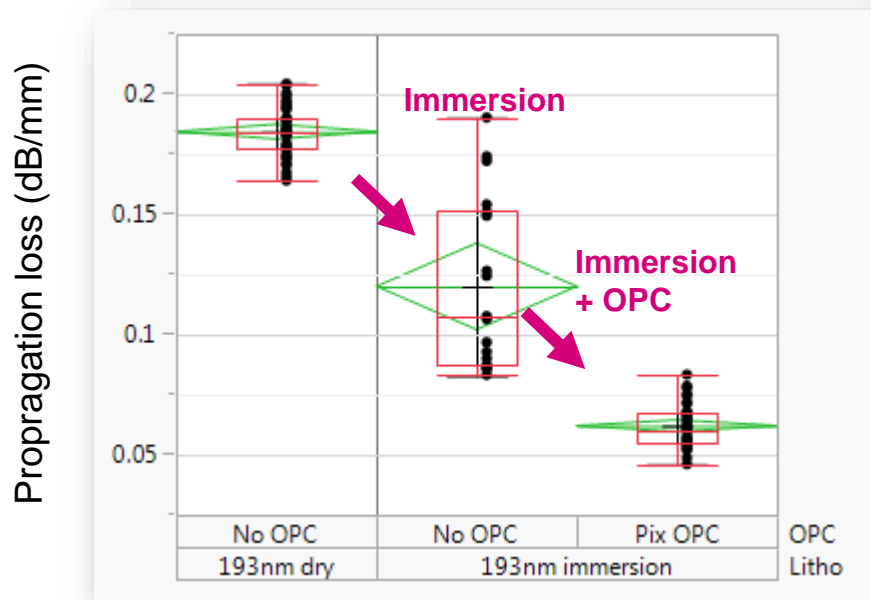
High accuracy in silicon patterning leads to:

- Lower optical losses
- Lesser need for active signal control (power consumption reduction)

Using 193nm Immersion Lithography in Si-Photonics

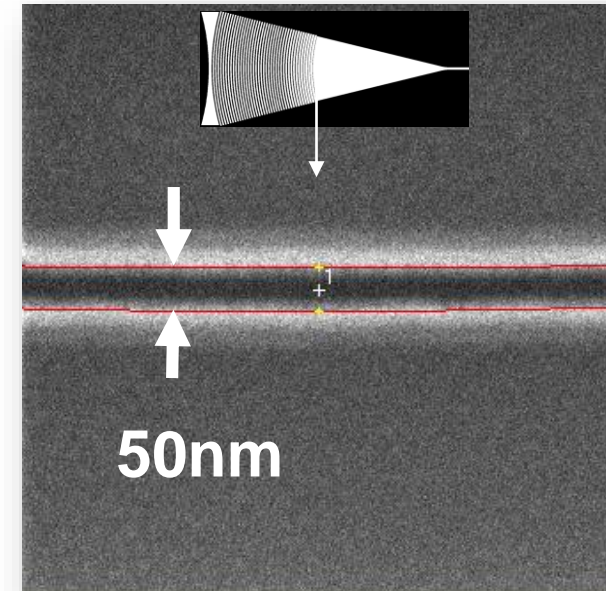
Reduced propagation losses

SMW : 1.8dB/cm → 0.6 dB/cm



Better I/O resolution

Improved performance



Using 193i lithography for Si-Photonics is useful even for BIG devices!

SiN as a Photonic Material

Moderate index contrast

$\Delta n = 0,5$ $\Delta n = 2$

- ✓ $n_{\text{eff}}(\Delta W)/6$ compared to SOI
- Low spurious reflections
- Low propagation losses

Temperature tolerant

$<20\text{pm}/^\circ\text{C}$

Courtesy of C. Ramos

- ✓ $n_{\text{eff}}(\Delta T)/5$ vs SOI
- No thermal stabilization
- **Low power**

Large transparency range

Wavelength (μm)

- ✓ Visible to mid-IR
- ✓ “No” NL absorption
- Expand SiP application range

CMOS material

SiN Spacers Etch Stop/Isol.

- ✓ Mature manufacturing
- ✓ Reliability
- ✓ Low deposition T

SOI

- ✓ Active devices
- ✓ Footprint
- ✗ Env./Fab. Sensitivity
- ✗ Power Limitation

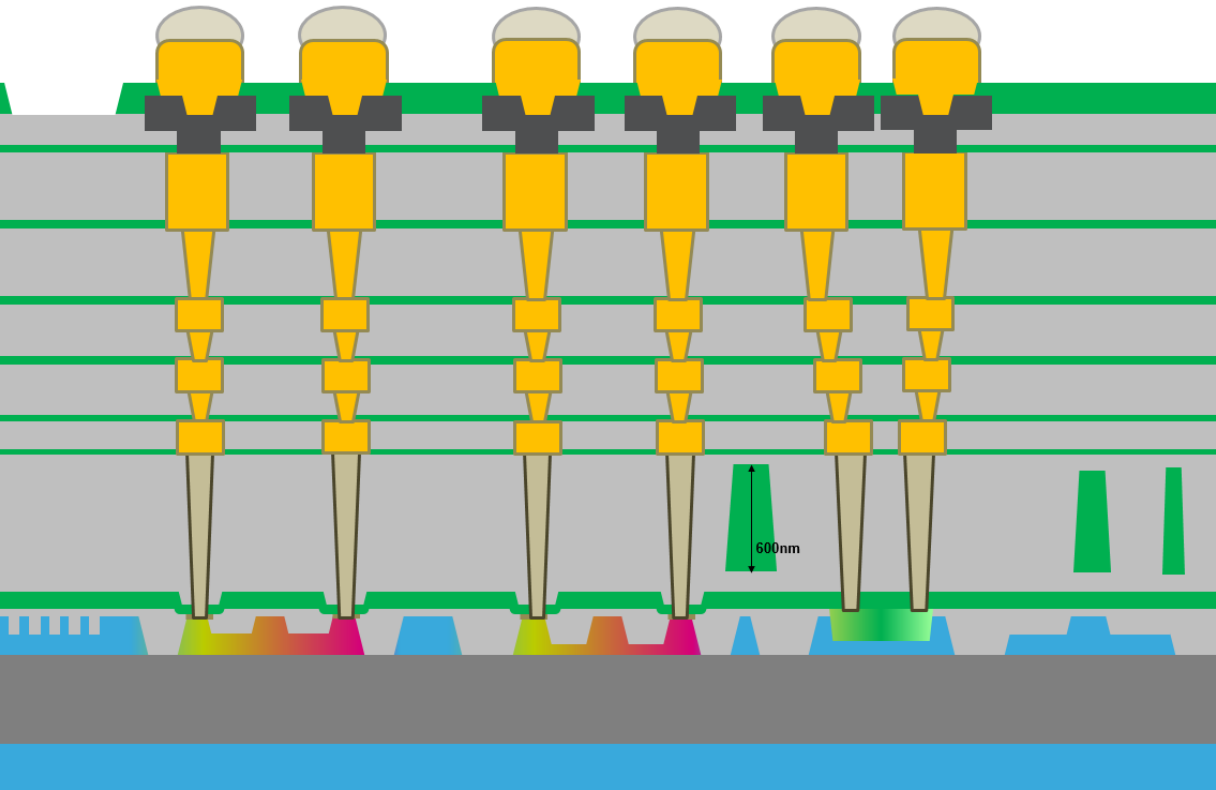
Complementary Platforms

SiN

- ✓ Env./Fab. tolerance
- ✓ Application range
- ✗ Footprint
- ✗ Passive only

Co-integration

Integrated Silicon Nitride Layer

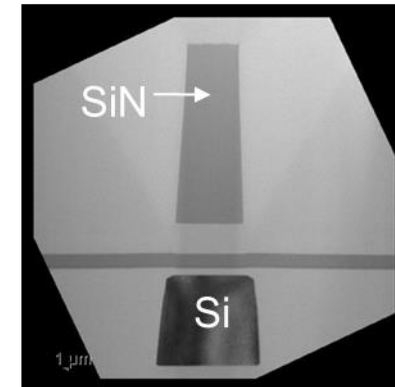
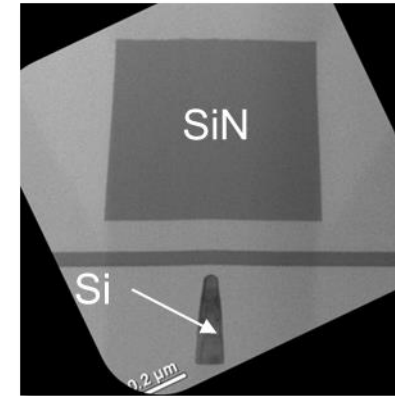


Metallic Interco

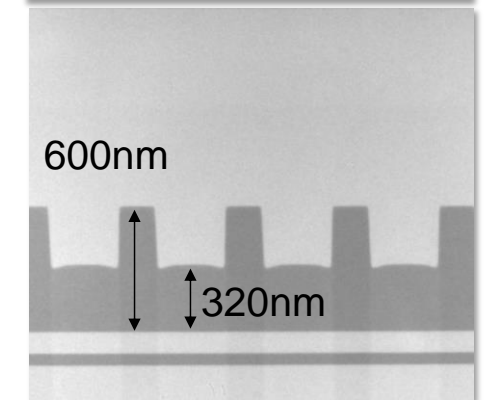
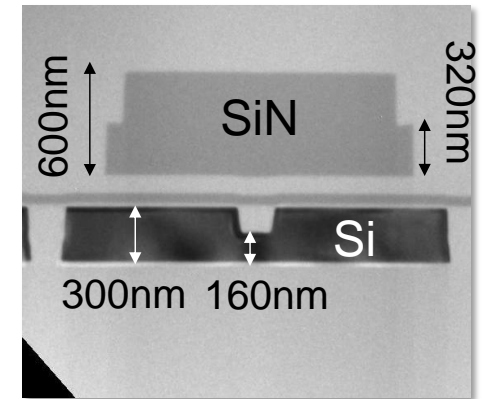
SiN WG 3D layer

Silicon devices

Si ↔ SiN transition



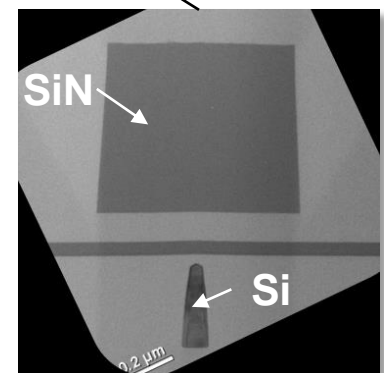
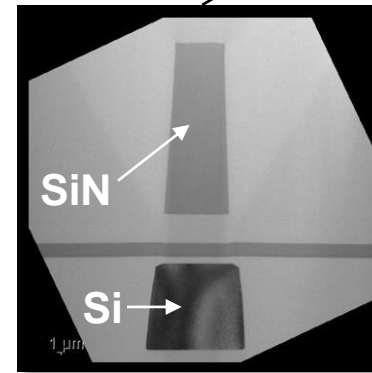
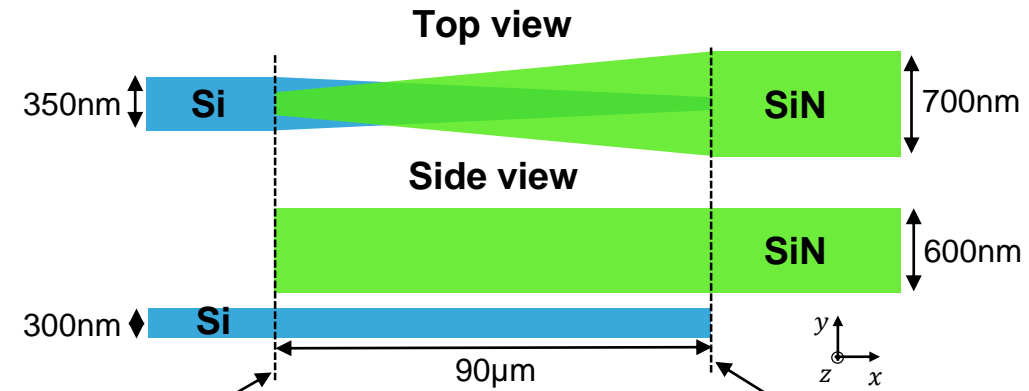
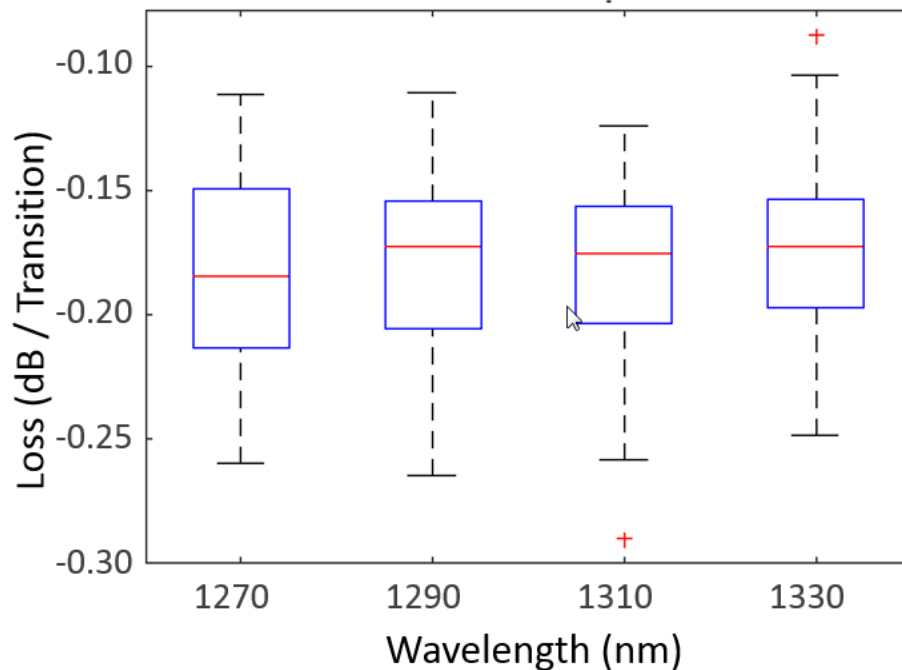
Strip & Rib SiN waveguides



Silicon nitride layer deposited and patterned within the contacts for the fabrication of additional passive devices.

Signal Propagation in SiN at $\lambda = 1310\text{nm}$

- Strip Waveguide Linear Transmission Losses = **0.6dB/cm**
- Rib Waveguide Linear Transmission Losses < **0.1dB/cm**
- 90° Strip Bend losses (Radius $\geq 40\mu\text{m}$) = **0.01dB/Bend**
- Si \leftrightarrow SiN adiabatic coupling < **0.25dB/Transition**:



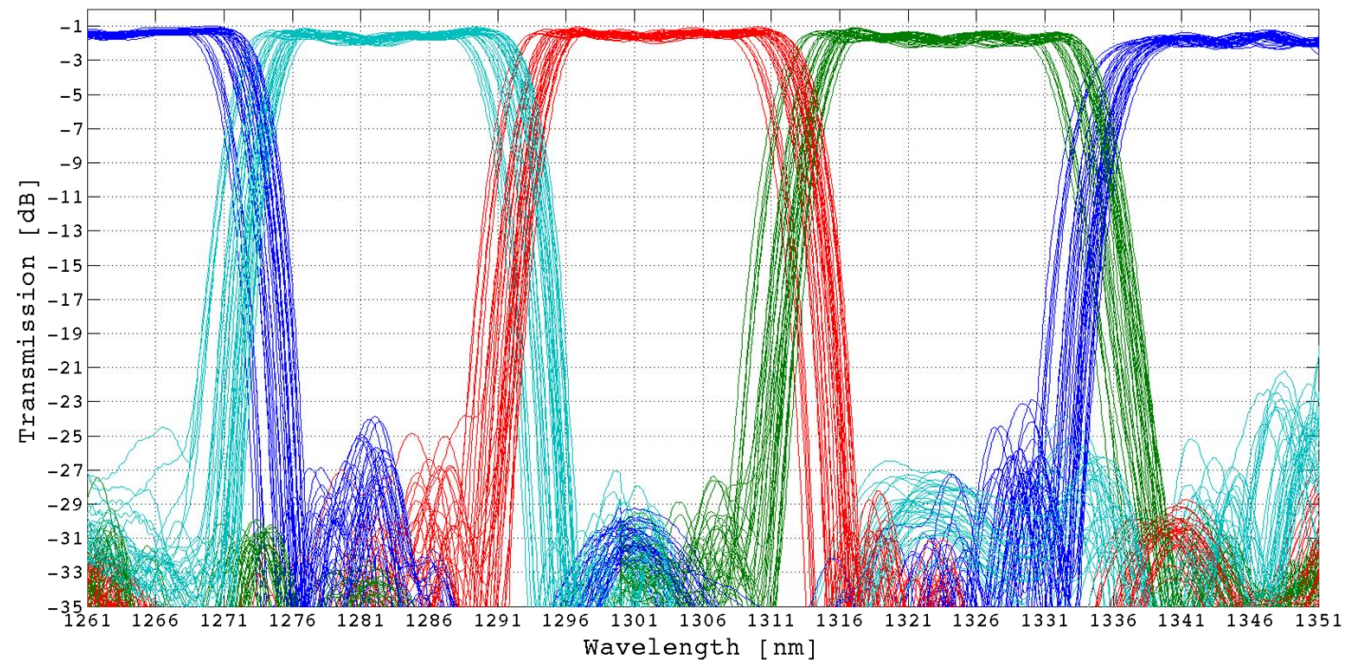
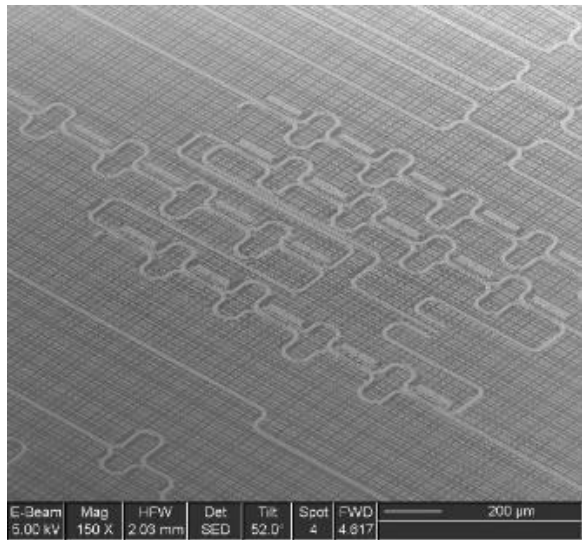
Published: GUERBER et al. (ST) SPIE Photonics EU (2018)

- Transition from Si to SiN devices is feasible within the same circuit

DEMUX: Cascaded Mach Zehnder Interferometer

Coarse Wavelength Division Multiplexing applications (CWDM) : 4λ separated by 20nm

- Spec over 14 nm bandwidth
 - Loss typical: 3 dB
 - Loss worst: 4 dB
 - X-Talk worst: 20 dB

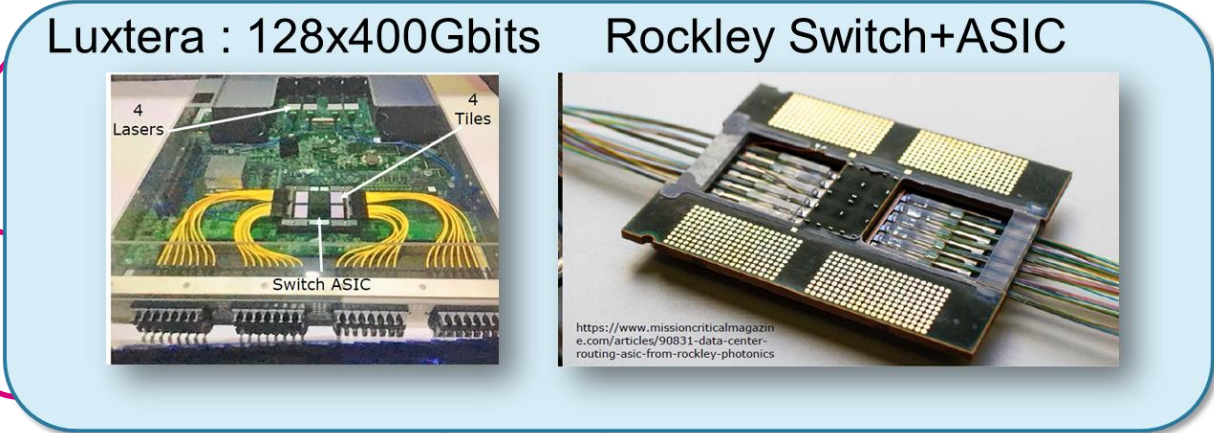
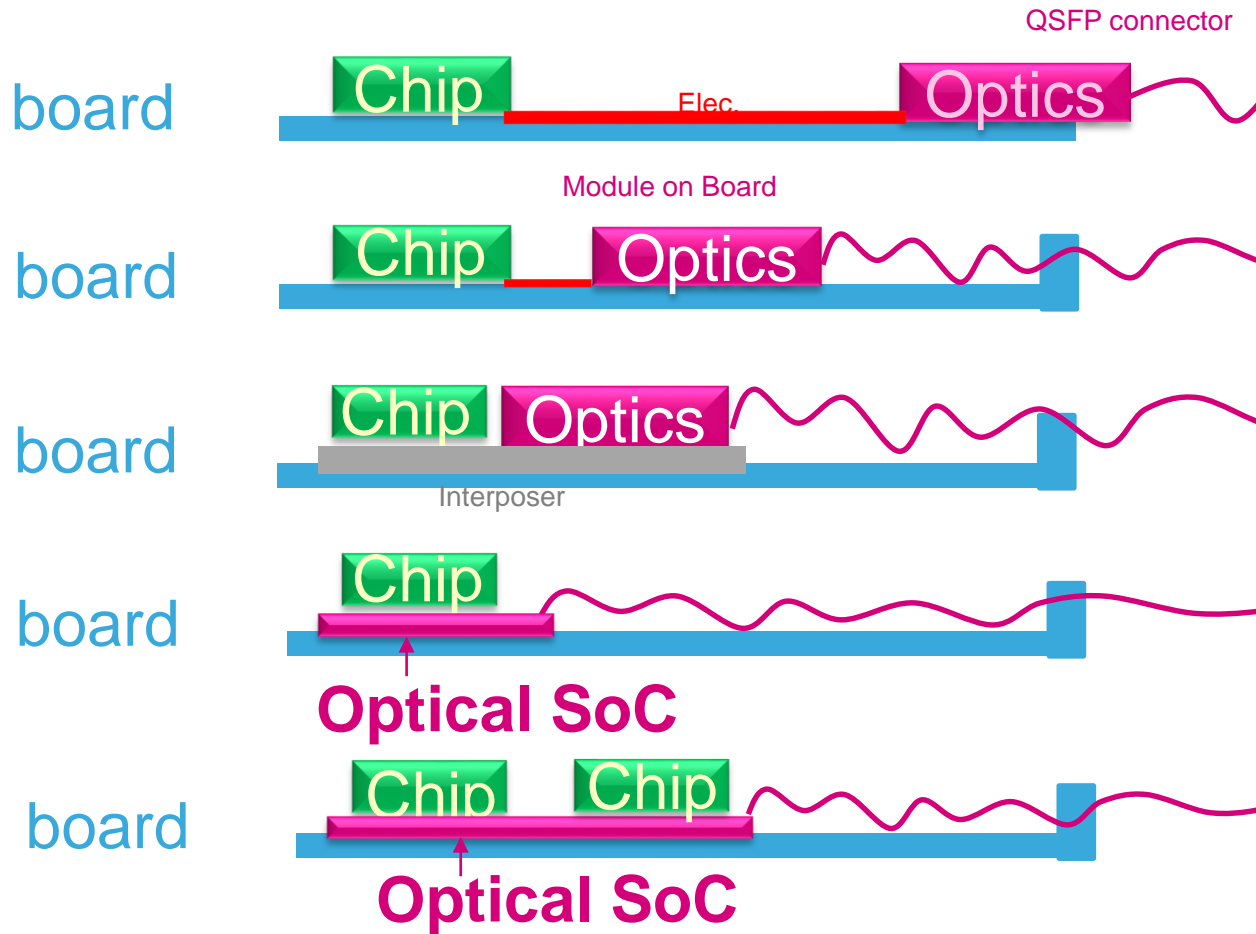


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And later ? What should Emerge ?

IEEE Standard : today 100G, 200G,400G, tomorrow 800G,.....,3.2TB

Switch applications and HPC needs : 3.2 TB, 6.4 TB, 12TB/s... 25.6 TB/s



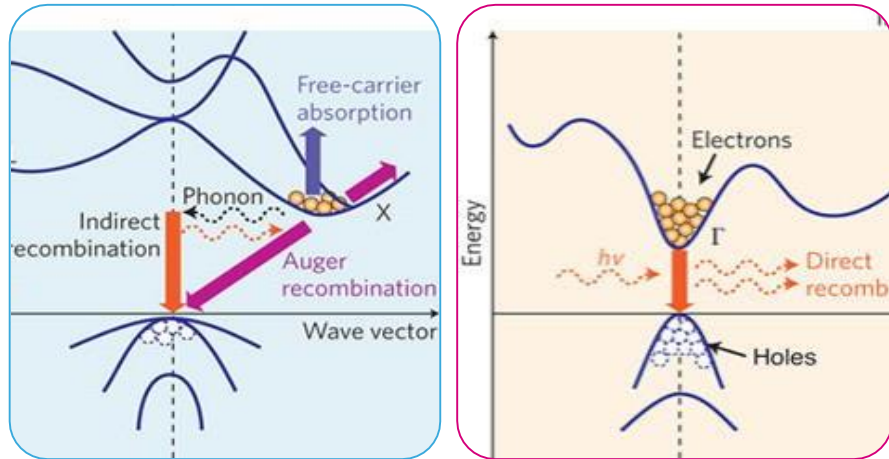
Ultimately, optics becomes an **active interposer**

Small footprint TX
Low power
Integrated lighsource ?

~25 to 50Tb/s
~256 channels

Light Source

Si : indirect bandgap InP : direct bandgap



Di Liang et al., Nat. Phot. Feb. 2010

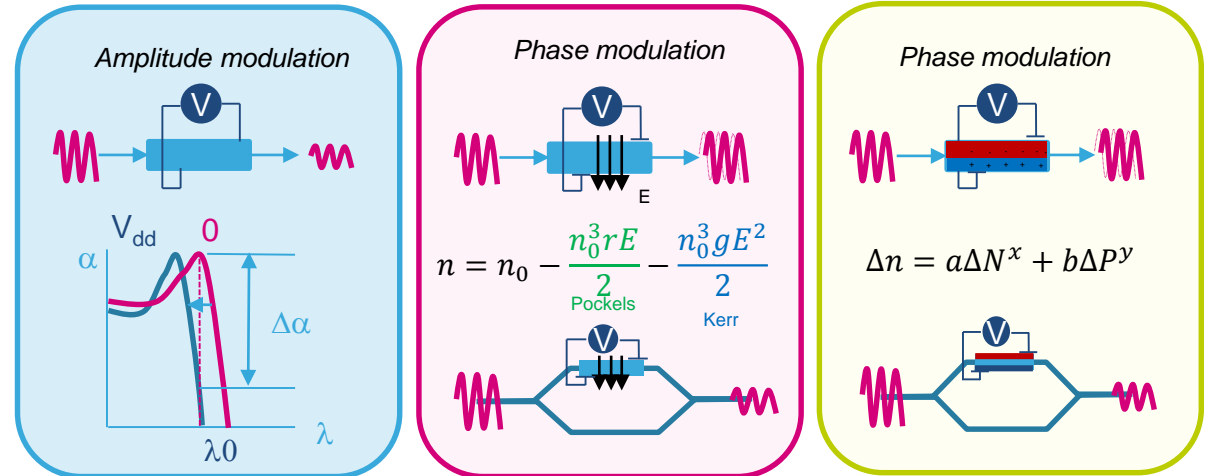
Si laser : low efficiency
 GeSn Laser : low maturity, $\lambda > 1.6\mu\text{m}$

Need to rely on III-V



Modulator Footprint

Electro Absorption Electro Refraction Plasma Dispersion



Si	✗	✗	✓
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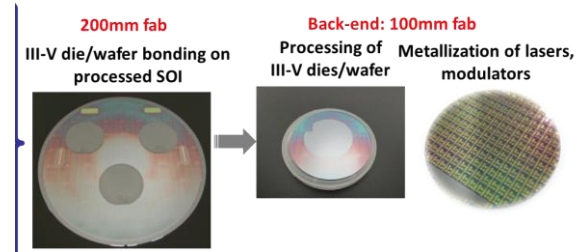
Limited efficiency → long devices

III-V	✓	✓	✓
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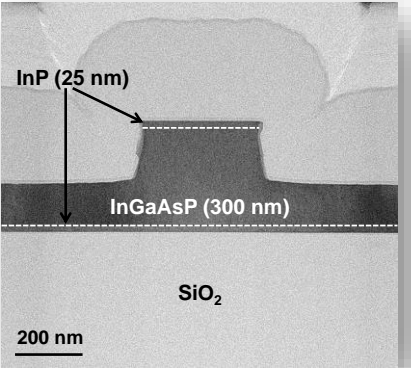
Ge/SiGe	✓	✓	✓
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Improved Devices using III-V Integration

III-V integration by wafer/patch bonding

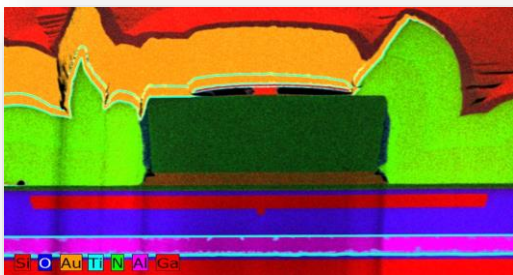


III-V-OI



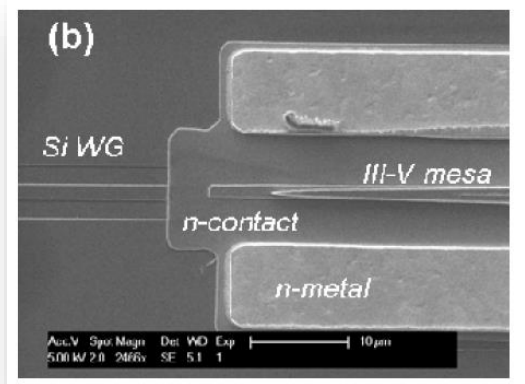
Y. Ikku et al. U. of Tokyo, Optics Express, 20, B357, 2012

Hybrid III-V/Si Laser



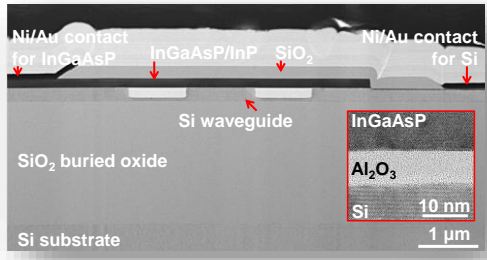
B. Ben Bakir, et al. " Opt. Express 19(11),(2011), LETI.
J. Durel et al (ST/LETI), IEDM 2016

Hybrid III-V/Si Electro-Absorption Modulator



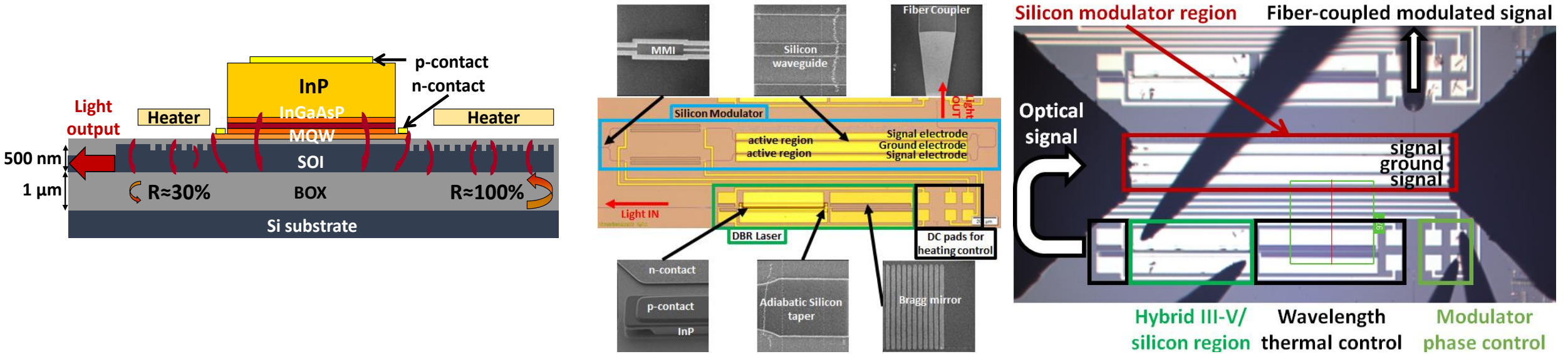
Y.H. Kuo et al. (UCSB),2008

Hybrid III-V/Si MOS-Modulator



J.H. Han et al. IEDM 2016, U-Tokyo

Integrated Transmitter : Hybrid Laser + Modulator



- Demonstration of a **25 Gb/s** transmission using the transmitter, with 2.5 Vpp on each MZM arm.



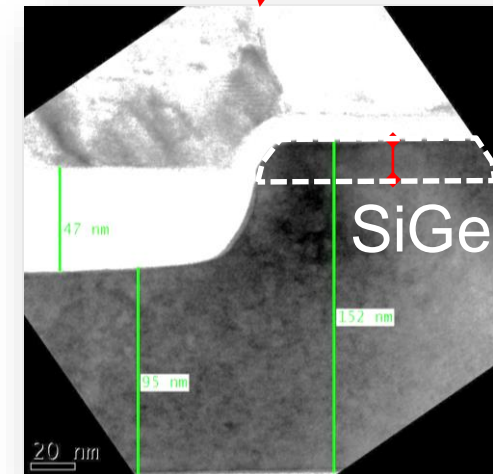
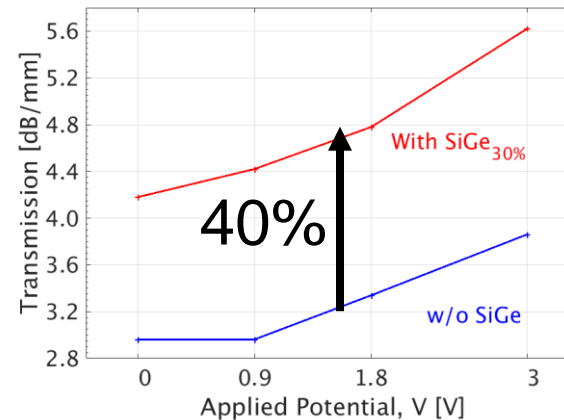
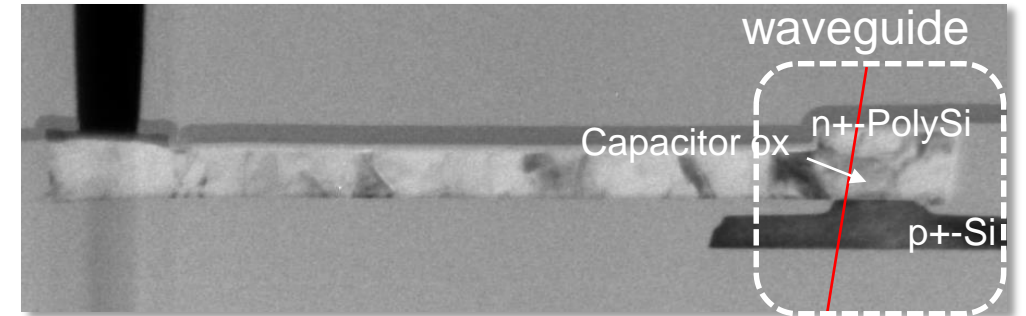
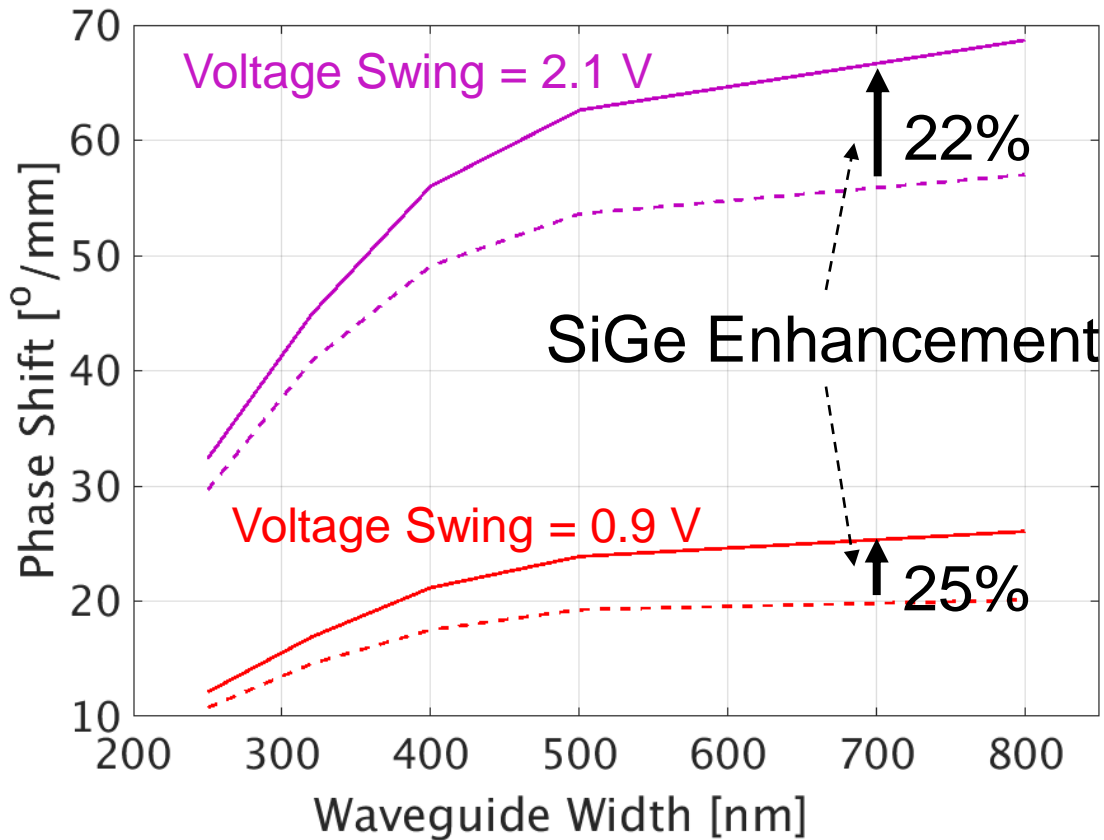
T.Ferrotti et al.,
SSDM 2016,
Optics Express
2017 , CEA-
LETI/ST



MOS Modulator using SiGe at interface

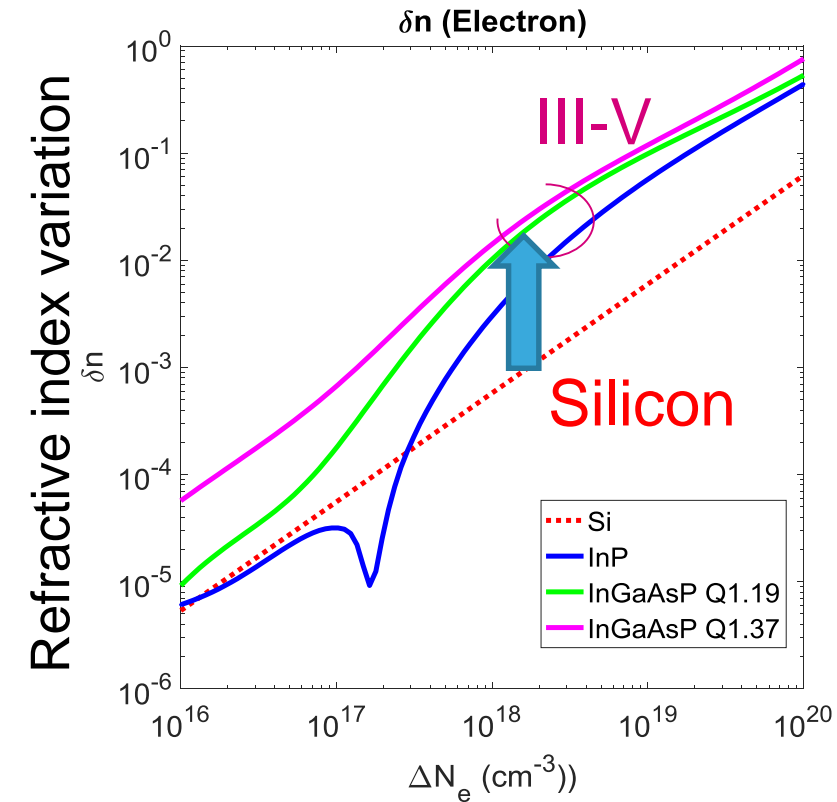
29

- 15 nm of SiGe_{0.3} is grown on the silicon waveguide before interface oxide deposition ($T_{ox} = 13\text{nm}$)

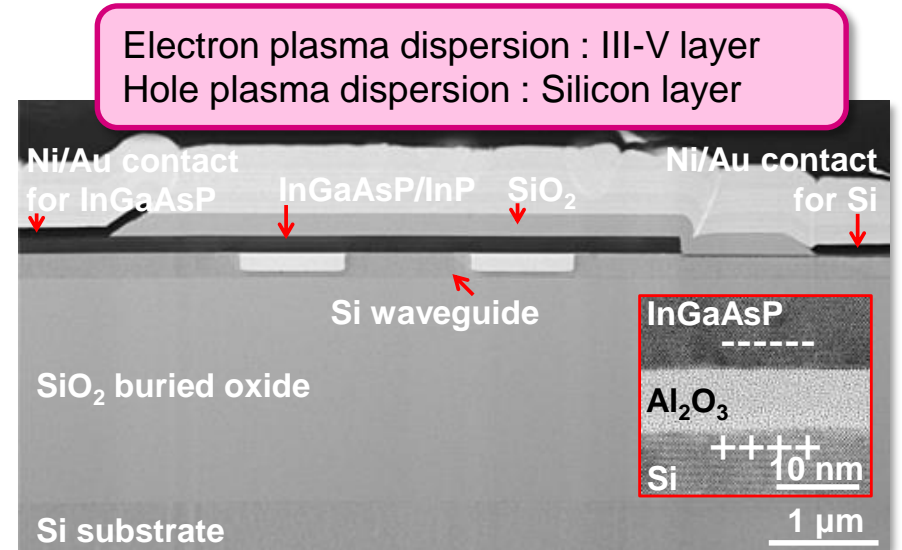
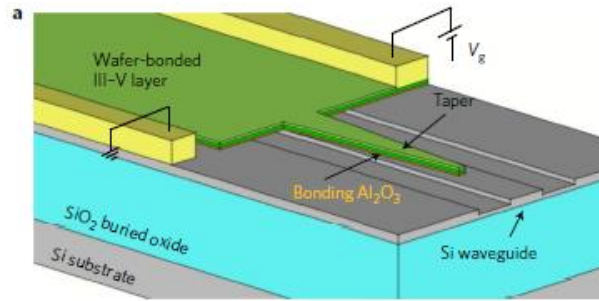


- 25% improvement in efficiency measured when using SiGe in capacitive structure

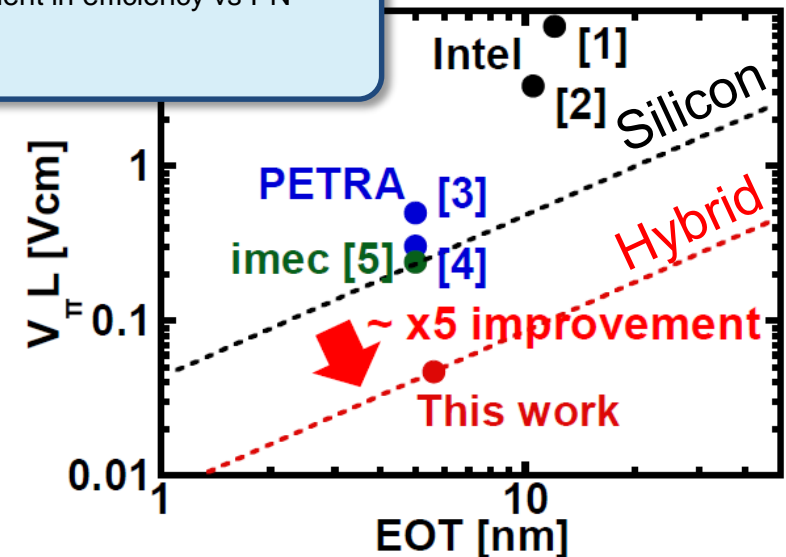
Heterogeneous Integration on SOI : Efficient Modulation



Carrier Density Variation



50X improvement in efficiency vs PN junction
5X versus Si



Secured
Communication

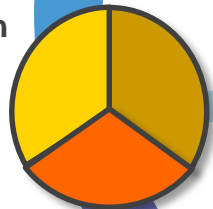
Sensing

Datacom

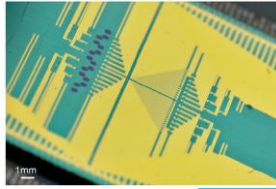
Bandwidth

Insertion Loss

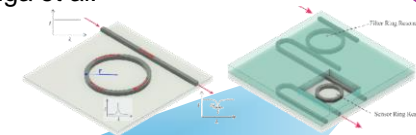
Power Management



Quantum Computing
Ji Wang et al., Science



Silicon-Based Optical Biosensors
Laura Lechuga et al.

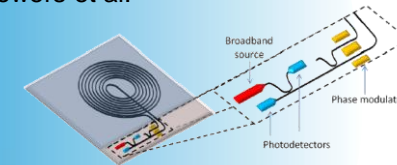


More than DATACOM

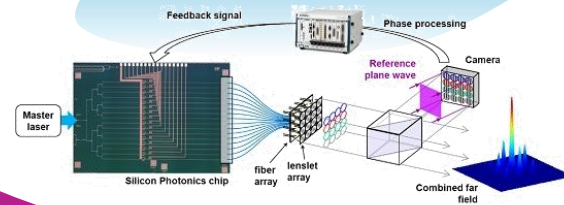
Photonic sensors & detectors connecting objects



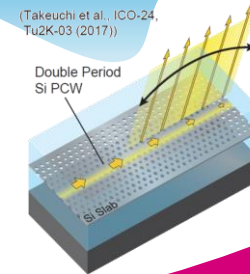
Hybrid silicon waveguide optical gyroscope
John Bowers et al.



Atmospheric LiDAR anemometer
Jérôme Bourderionnet et al.



Photonic Crystal based Lidar
T. Baba et al.

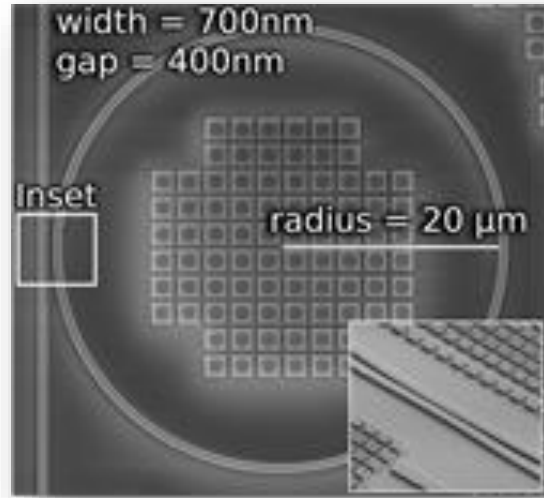


(Takeuchi et al., ICO-24, Tu2K-03 (2017))

Automotive

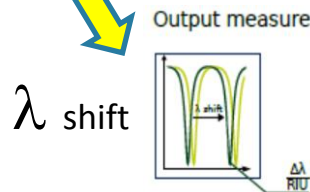
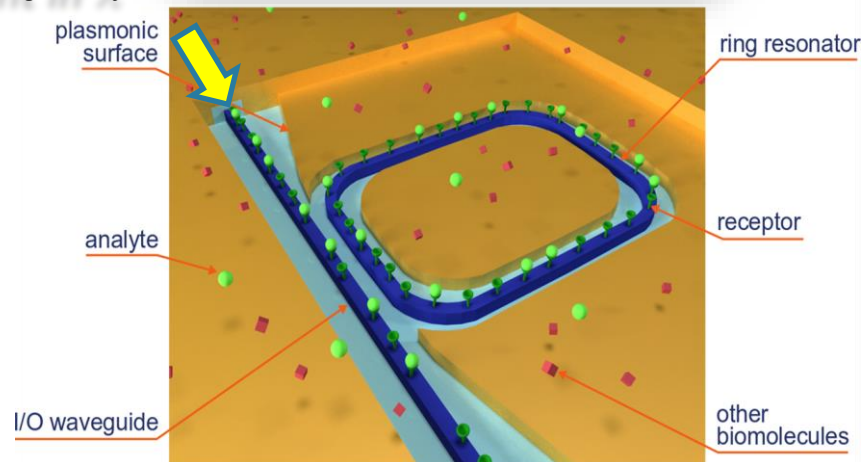
Optical Sensor using DAPHNE

SiN ring resonator

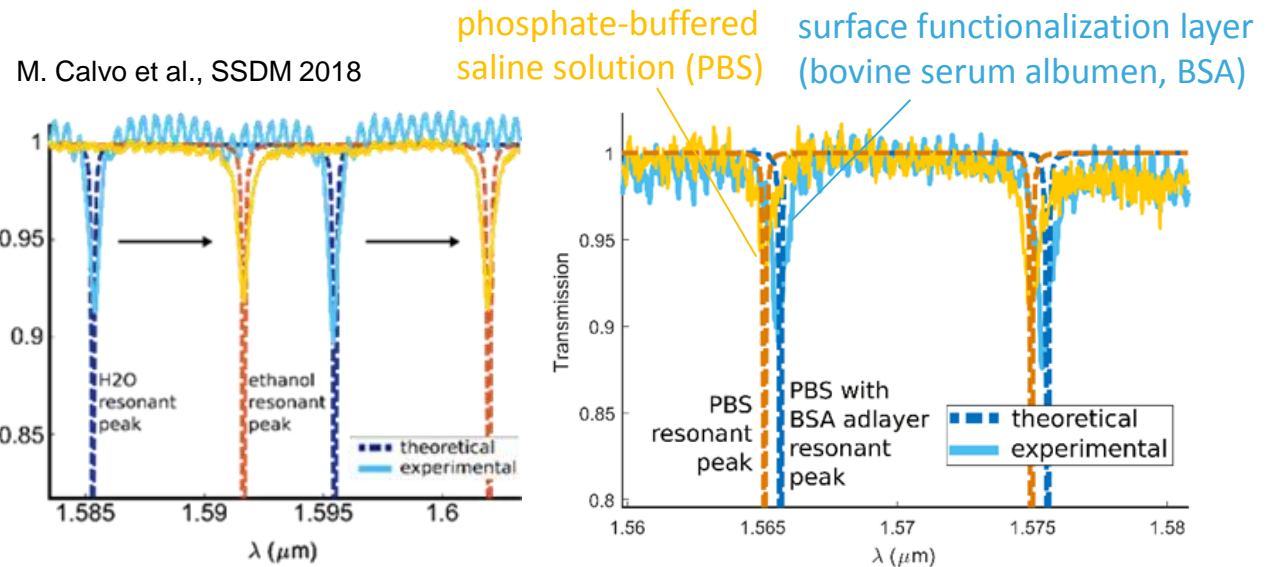


Molecules adsorption modifies effective optical index on the ring resonator surface Resonant peak shift with this effective index

Light in λ



Light out



0.5 nm resonant peak shift per nm thickness change in biological add layer

- After 20 years of research and development , Silicon Photonics became an industrial reality thanks to the increase of Datacenter-Applications
- Despite relatively large feature size compared to advanced CMOS, Si-Photonic requires advanced processing tools to guarantee high-yield
- Basic building blocks have a high maturity level, but performance improvement are still mandatory to adress the IEEE ethernet roadmap and ultimately the chip-to-chip communication market
- Heterogeneous Integration of materials with Silicon, such as Ge or III-V, and TSV is a promising path to demonstrate complex optical SoC to adress several 10s of Tb/s communications
- Research on Si-Photonics for « More Than Datacom » is very active at the international level

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